

Test methods for electrical materials, printed board and other interconnection structures and assemblies - Part 5-504: General test methods for materials and assemblies - Process ionic contamination testing (PICT)

EESTI STANDARDI EESSÕNA

NATIONAL FOREWORD

See Eesti standard EVS-EN IEC 61189-5-504:2020 sisaldab Euroopa standardi EN IEC 61189-5-504:2020 ingliskeelset teksti.	This Estonian standard EVS-EN IEC 61189-5-504:2020 consists of the English text of the European standard EN IEC 61189-5-504:2020.
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English Version

Test methods for electrical materials, printed board and other
interconnection structures and assemblies - Part 5-504: General
test methods for materials and assemblies - Process ionic
contamination testing (PICT)
(IEC 61189-5-504:2020)

Méthodes d'essai pour les matériaux électriques, les cartes
imprimées et autres structures d'interconnexion et
ensembles - Partie 5-504: Méthodes d'essai générales pour
les matériaux et les ensembles - Essai de contamination
ionique des procédés (PICT)
(IEC 61189-5-504:2020)

Prüfverfahren für Elektromaterialien, Leiterplatten und
andere Verbindungsstrukturen und Baugruppen - Teil 5-
504: Allgemeine Prüfverfahren für Materialien und
Baugruppen - Prüfung der ionischen Verunreinigung bei
Prozessen (PICT)
(IEC 61189-5-504:2020)

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Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

European foreword

The text of document 91/1639/FDIS, future edition 1 of IEC 61189-5-504, prepared by IEC/TC 91 "Electronics assembly technology" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 61189-5-504:2020.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2021-02-26
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Annex ZA

(normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60068-1	-	Environmental testing - Part 1: General and guidance	EN 60068-1	-
IEC 60068-2-20	-	Environmental testing - Part 2-20: Tests - Test T: Test methods for solderability and resistance to soldering heat of devices with leads	EN 60068-2-20	-
IEC 60068-2-58	-	Environmental testing - Part 2-58: Tests - Test Td: Test methods for solderability, resistance to dissolution of metallization and to soldering heat of surface mounting devices (SMD)	EN 60068-2-58	-
IEC 60079-7	-	Explosive atmospheres - Part 7: Equipment protection by increased safety "e"	EN 60079-7	-
IEC 60194	-	Printed board design, manufacture and assembly - Terms and definitions	-	-
IEC 61189-5-502	-	Test methods for electrical materials, printed boards and other interconnection structures and assemblies - Part 5-502: General test methods for materials and assemblies - Surface insulation resistance (SIR) testing of assemblies	-	-
IEC 61190-1-3	-	Attachment materials for electronic assembly - Part 1-3: Requirements for electronic grade solder alloys and fluxed and non-fluxed solid solder for electronic soldering applications	EN IEC 61190-1-3	-
IPC-TM-650 method 2.6.3.7	-	Surface Insulation Resistance	-	-

IPC 9202	-	Material and Process Characterisation / Qualification Test Protocol for Assessing Electrochemical Performance	-	-
IPC 9203	-	Users Guide to IPC 9202 and the IPC-B-52 Standard Test Vehicle	-	-

INTERNATIONAL STANDARD

NORME INTERNATIONALE



**Test methods for electrical materials, printed board and other interconnection structures and assemblies –
Part 5-504: General test methods for materials and assemblies – Process ionic contamination testing (PICT)**

**Méthodes d'essai pour les matériaux électriques, les cartes imprimées et autres structures d'interconnexion et ensembles –
Partie 5-504: Méthodes d'essai générales pour les matériaux et les ensembles – Essai de contamination ionique des procédés (PICT)**



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Partie 5-504: Méthodes d'essai générales pour les matériaux et les ensembles – Essai de contamination ionique des procédés (PICT)**

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CONTENTS

FOREWORD	4
1 Scope	6
2 Normative references	6
3 Terms and definitions	7
4 General description of the test	7
5 Test apparatus	7
6 Materials	8
6.1 Test solution	8
6.1.1 General	8
6.1.2 Deionised water (DI)	8
6.1.3 Propan-2-ol	9
6.2 Calibration solution	9
6.3 Test chamber	9
6.4 Regeneration filter column	9
6.5 Recirculating pump	9
6.6 Measurement system capability	9
7 Test procedure	9
7.1 Test apparatus	9
7.2 Closed loop	10
7.3 Open loop	11
7.4 System verification	12
7.4.1 General	12
7.4.2 Polishing the test solution	12
7.4.3 Recording test solution temperature and specific gravity	12
7.4.4 Checking conductivity accuracy	13
7.5 Procedure	14
7.5.1 Specimen handling	14
7.5.2 General	14
7.5.3 Closed loop	14
7.5.4 Open loop	15
7.5.5 Influence of CO ₂	15
8 Measurement Methods	16
8.1 Method 1	16
8.2 Method 2	17
Annex A (normative) Test technique	18
A.1 Conductivity signal	18
A.2 DI water correction	18
A.3 Conductivity of the ionic solution	19
A.3.1 General	19
A.3.2 Conductivity differences	20
A.4 Test solution temperature	20
A.4.1 General	20
A.4.2 Linear temperature	20
A.4.3 Leaching effects	20
A.5 Conversion of conductivity to contamination	21
A.6 Calibration	21

Annex B (informative) Measurement methods	22
B.1 Method 1	22
B.2 Method 2	24
Bibliography	25
Figure 1 – Typical test instrument	8
Figure 2 – Closed-loop method in regeneration mode	10
Figure 3 – Closed loop in test mode	11
Figure 4 – Open loop method	12
Figure 5 – 50 % specific gravity chart	13
Figure 6 – 75 % specific gravity chart	13
Figure 7 – Example of result measuring the influence of CO ₂	16
Figure A.1 – Conductivity against voltage curve	18
Figure A.2 – Deionised water correction	19
Figure B.1 – Test pass	23
Figure B.2 – Test fail	23
Table B.1 – Pass/Fail value method 1 worked example	22

INTERNATIONAL ELECTROTECHNICAL COMMISSION

TEST METHODS FOR ELECTRICAL MATERIALS, PRINTED BOARDS AND OTHER INTERCONNECTION STRUCTURES AND ASSEMBLIES –

Part 5-504: General test methods for materials and assemblies – Process ionic contamination testing (PICT)

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FDIS	Report on voting
91/1639/FDIS	91/1644/RVD

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This document has been drafted in accordance with the ISO/IEC Directives, Part 2.